

Title (en)

METHOD AND DEVICE FOR ANALYSING THE SURFACE OF A SUBSTRATE

Title (de)

VERFAHREN UND EINRICHTUNG ZUR ANALYSE DER OBERFLÄCHE EINES SUBSTRATS

Title (fr)

PROCEDE ET DISPOSITIF D'ANALYSE DE LA SURFACE D'UN SUBSTRAT

Publication

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Application

**EP 01997186 A 20011121**

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Abstract (en)

[origin: WO0242715A1] The invention concerns a method for analysing a substrate (2) surface which consists in providing a reflection image of at least a target (1) on said surface, retrieving by digital processing local phases along two directions. The invention is characterised in that it consists in calculating by digital processing based on the local phases, local slope variations to deduce therefrom curvature variations or altitude variations of said surface.

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IPC 8 full level

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